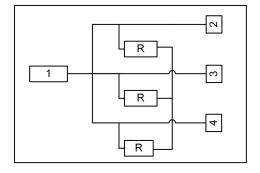
GaAs MMIC monolithic integrated 3-way 0 degree power divider, 6-18GHz

Performance characteristics

- Frequency range: 6-18GHz
- Insertion loss : 0.5 dB
- 500hm input / output
- 100% on-wafer testing
- Chip size: 1.8 x 1.2 x 0.1mm

Functional Block Diagram



Product Introduction

The GPD-06183 monolithic integrated 3-way 0- degree power divider has low insertion loss and excellent port standing wave characteristics in the frequency range of 6~18GHz, with an isolation of 18dB, and is very suitable for microwave hybrid integrated circuits and multi-chip modules. The chip uses on-chip through-hole metallization technology to ensure good grounding, does not require additional grounding measures, and is simple and convenient to use.

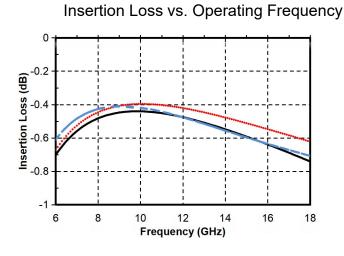
Use restriction parameter ¹		
Maximum input power	+40dBm	
Operating temperature	-55 ~ +85°C	
storage temperature	-65 ~ +150°C	

[1] Exceeding any of these maximum limits may cause permanent damage.

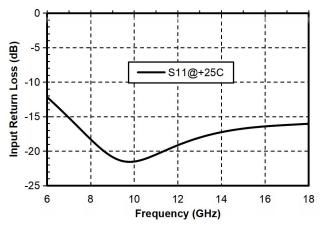
Electrical performance parameters (TA = +25°C)					
index	Minimum	Typical Value	Maximum	unit	
Frequency Range	6-18			GHz	
Insertion loss	0.4	0.5	0.8	dB	
Insertion loss fluctuation		± 0.2		dB	
Isolation	18	25	-	dB	
Input return loss	12	15	-	dB	
Output return loss	17	24	-	dB	

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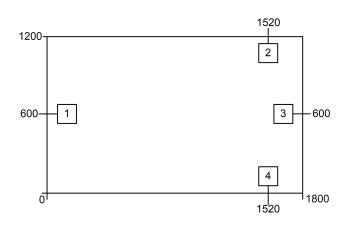
Main index test curve



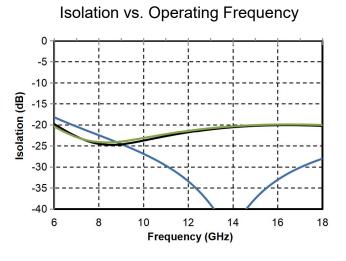
Input Return Loss vs. Operating Frequency



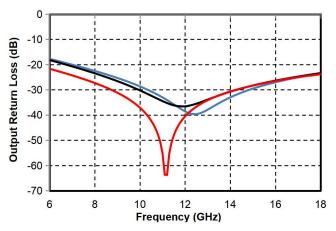
Appearance structure ²



【 2 】 All units in the figure are micrometers



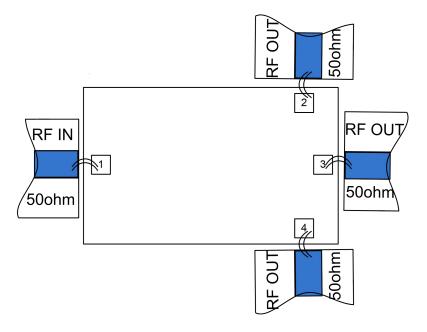
Output Return Loss vs. Operating Frequency



GaAs MMIC monolithic integrated 3-way 0 degree power divider , 6-18 GHz

Bonding point definition					
Bonding point	Function	Functional Description	Equivalent Circuit		
number	Symbol				
1	RF IN	RF signal input terminal			
2, 3, 4	RF OUT	RF signal output terminal	RF Out		
Chip bottom GND	The bottom of the chip needs to be	GND			
	well grounded to RF and DC				

Recommended assembly drawing



Precautions for use

- The chip needs to be stored in an anti-static container and kept in a nitrogen environment.
- Do not attempt to clean the bare die surface using wet chemical methods.
- Please strictly comply with ESD protection requirements to avoid electrostatic damage to bare chips.
- General operation: Please use precision pointed tweezers to pick up bare chips. Avoid touching the chip surface with tools or fingers during operation.
- Rack mounting operation suggestions: Bare chip mounting can be done by AuSn solder eutectic sintering or conductive adhesive bonding. The mounting surface must be clean and flat.
- Sintering process: It is recommended to use AuSn solder sheets with a gold-tin ratio of 80/20 . The working surface temperature reaches 255 °C and the tool (vacuum chuck) temperature reaches 265 °C. When the high-temperature mixed gas (nitrogen-hydrogen ratio of 90/10) is

blown to the chip, the temperature at the top of the tool should be raised to 290 $^{\circ}$ C. Do not let the chip exceed 320 $^{\circ}$ C for more than 20 seconds. The friction time should not exceed 3 seconds.

- Bonding process: The amount of conductive glue dispensed should be as small as possible. After the chip is placed in the installation position, the conductive glue should be vaguely visible around it. For curing conditions, please follow the information provided by the conductive glue manufacturer.
- Bonding operation suggestions: Use Φ0.025mm (1mil) gold wire for both ball and wedge bonding. Thermo-ultrasonic bonding temperature is 150 °C. The pressure of the wedge for ball bonding is 40~50gf , and the pressure of the wedge bonding is 18~22gf . Use the smallest possible ultrasonic energy. The bonding starts at the pressure point on the chip and ends at the package (or substrate).